

by Andrii Koniv 2016 Cited by 5 July 21, 2016 (87)
1(2014)3088-2999 D2. **AIM:** The goal of the study was to design and evaluate an on-chip SAW sensor. The sensor was designed for real-time monitoring and fingerprint identification and was tested on human finger samples using three different SAW materials. **METHODS:** The SAW sensors were fabricated on a high piezoelectric Y-X LiNbO₃ substrate by using a conventional photolithography-based etching process and titanium as the SAW and interdigital transducer (IDT) electrode material. All SAW sensors were activated in air and the resulting devices were then tested for robustness against water vapor and human finger swipe contact. **RESULTS:** A correlation of finger-print features was found for on-chip SAW sensors using three different substrates: HT (100%). MOI (100%). US (100%). The devices showed a 4.4 times signal increase for substrates HT and US compared to the conventional SAW (50%) substrates. For the case of the MOI substrate, a significant signal decrease was observed. For sensors fabricated on MOI (100%), the activation of the device in air resulted in a signal decrease of 34% for the device HT (100%) and 15% for the device HT (50%). The increased moisture resistance of the substrate US (100%) and decreased stability of the device HT

(100%) resulted in an increased degradation rate for the device HT (100%) of -15%. With regard to the SAW sensors activated with human finger swipe contact, a consistent signal decrease was observed. CONCLUSION: In conclusion, the on-chip SAW device was shown to be significantly affected by moisture. While the substrates MOI (100%) and US (100%) have shown better moisture resistance in comparison to conventional HT (50%) SAW devices, it is worth mentioning that all the MOI (100%) and US (100%) devices have been partially degraded, which resulted in a decrease in their performance. . The Linear Scanning Electrochemical Microscope. by Mark A. Elford 2018 Cited by 76 September 22, 2019, 113 (3) 997-1005, 103-104 A framework for automatic registration and optimization of STEM image contrast. by Adam N. Beaudet

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